Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/526,776	DAVISON, ERNIE	DAVISON, ERNIE	
Examiner	Art Unit		
Tran N. Nauven	2834		

Tran N. Nguyen

SEARCHED					
Class	Subclass	Date	Examiner		
310	75R	12/12/2007	/TN/		
	80-86		/TN/		
	209		/TN/		
	216		/TN/		
•	184-185		/TN/		
	190-191	A	/TN/		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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